

Supplementary information

**Spectroscopic and Electrical Signatures of Acceptor States in
Solution Processed Cu₂ZnSn(S,Se)₄ Solar Cells**

Devendra Tiwari^a, Ekaterina Skidchenko^b, Jake W Bowers^c, Michael V Yakushev^{b,d,e},
Robert W Martin^b and David J Fermin^{a,*}

^a School of Chemistry, University of Bristol, Bristol BS8 1TS, United Kingdom.

^b Department of Physics, SUPA, Strathclyde University, Glasgow G4 0NG, United Kingdom.

^c Centre for Renewable Energy Systems Technology (CREST), Wolfson School of Mechanical, Electrical and Manufacturing Engineering, Loughborough University, Loughborough LE11 3TU, United Kingdom.

^d Institute of Metal Physics UB RAS, 620990, S. Kovalevskaya Street 18, Ekaterinburg, Russia

^e Ural Federal University, Mira 19, 620002 Ekaterinburg, Russia

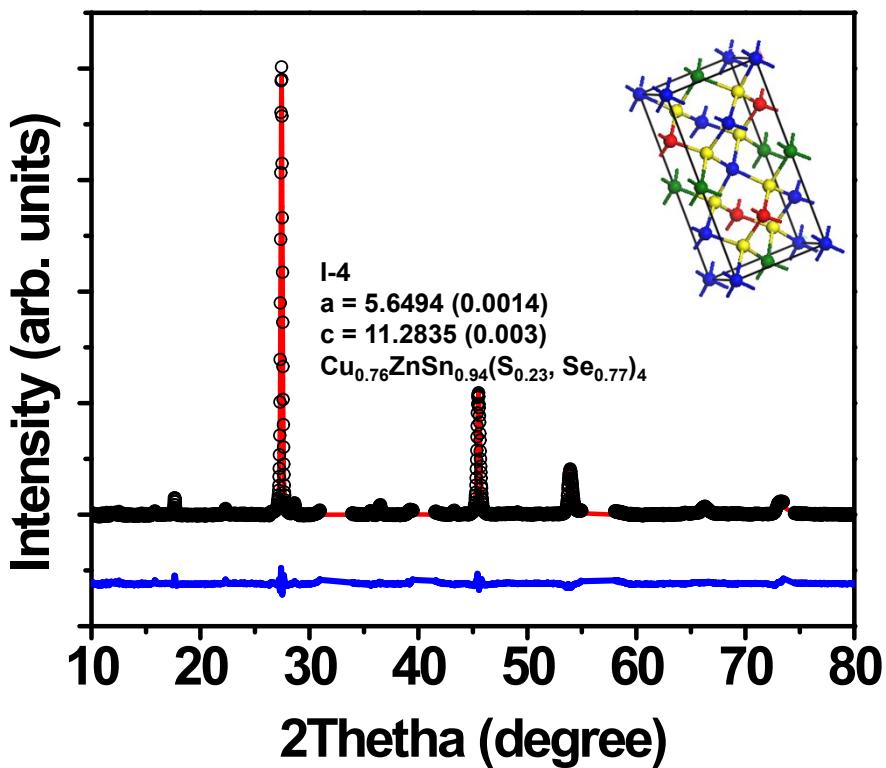


Figure s1: Quantitative Rietveld analysis of CZTSSe X-ray diffraction pattern, Inset shows the schematic of kesterite structure.

Table s1: Structural parameters derived from full profile Rietveld refinement of selective region of CZTSSe peaks in X-diffractogram.



Symmetry/ Space group	Tetragonal: I-4 (82)
Quality of fitting	$R_{wp} = 5.23\%$; $R_p = 3.82\%$
Lattice parameters	$a = 5.6494 \pm 0.0014 \text{ \AA}$
	$c = 11.2835 \pm 0.0035 \text{ \AA}$

Element	Wyckoff	x	y	z	occupancy
Cu	2a	0	0	0	0.7654
Zn	2d	0	0.5	0.75	1
Sn	2b	0	0	0.5	0.8988
Cu	2c	0	0.5	0.25	0.8363
S	8g	0.2504 ± 0.0032	0.2576 ± 0.0041	0.1283 ± 0.0067	0.2277
Se	8g	0.2504 ± 0.0032	0.2576 ± 0.0041	0.1283 ± 0.0067	0.7723

Table s2: Distribution of key cell parameters measured across 20 CZTSSe devices under simulated AM1.5G spectrum with power density of 100 mW/cm².

	V _{oc} (mV)	J _{sc} (mA/cm ²)	FF (%)	Efficiency (%)
Best	396	27.8	52.05	5.71
Mean	370	28.86	44.7	4.86
Std. Dev.	33	4.26	6.8	1.01

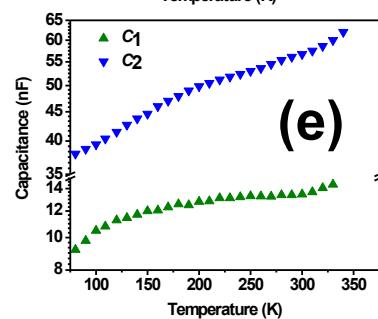
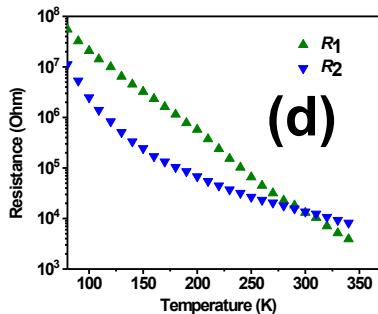
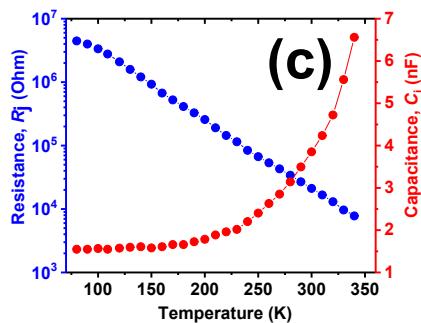
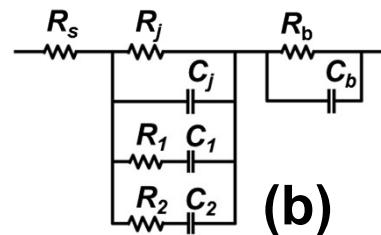
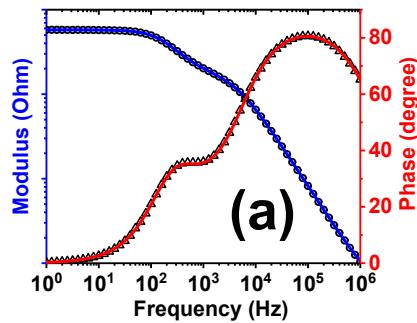


Figure s2: Low-temperature impedance spectroscopy of CZTSSe devices: (a) A typical spectrum with fitting and equivalent circuit used for fitting (b), temperature variation of (c) junction resistance, R_j and capacitance, C_j and of (d) resistances R_1 and R_2 and (e) capacitances C_1 and C_2 related to trap states.

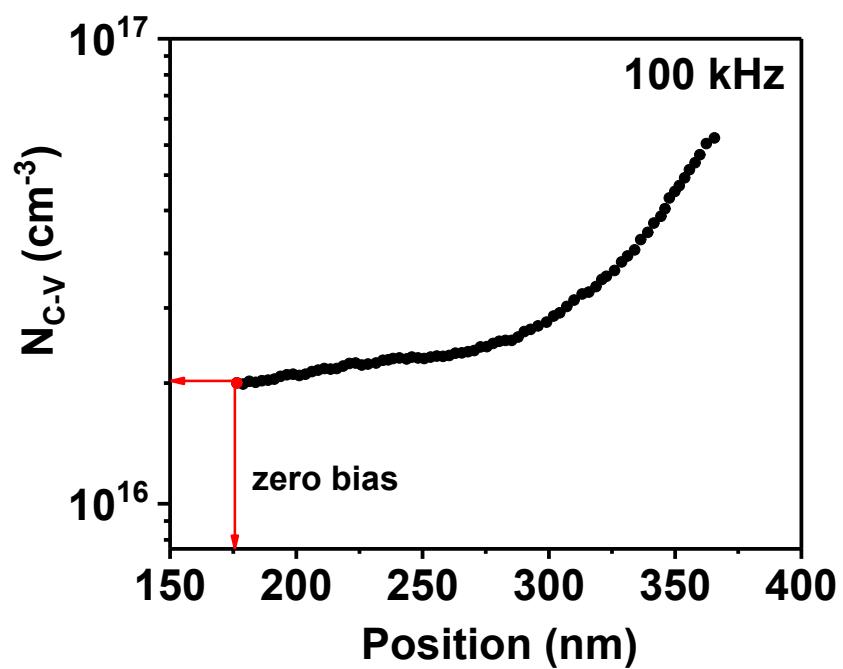


Figure s3: Capacitance-voltage profiling CZTSSe solar cell measured at 100 kHz and between 0 to -1.5 V with AC stimulus of 25 mV